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C Hu - Electron Devices Meeting, 1996., International, 1996 - ieeexplore.ieee.org  
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J Berntgen, T Lieske, B Schineller, M Deufel, M ... - Indium Phosphide and Related Materials, 1998 International ..., 1998 - ieeexplore.ieee.org  
 ... to get information about the **degradation** mechanisms inside ... This **stress** dependent change of the IV curves can be modeled by the equivalent **circuit diagram** shown ...  
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AE Kotov, K NOVA - Nonvolatile Memory Technology Conference, 1996., Sixth ..., 1996 - ieeexplore.ieee.org  
 ... during the entire stage of **degradation**, 2) when ... quantum yield of impact \_ionization, \_13+A3 **Stress** time charge ... Considering the capacitance equivalent circuit of T ...  
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R Menozzi - Semicond. Sci. Technol, 1998 - iop.org  
 ... techniques, to device and **circuit** processing and ... featured temperature-accelerated **stress** experiments, thus ... to thermally activated **degradation** mechanisms, such ...  
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B Sensor, A Center - ieeexplore.ieee.org  
 ... will not have any noticeable **degradation** for temperatures ... the drift, and package induced **stress** are common mode ... The detection **circuit** is located in the middle ...  
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N Kitawaki, H Nagabuchi - Communications Magazine, IEEE, 1988 - ieeexplore.ieee.org  
 ... T) implies the degree of **degradation** by transmission ... The quality of the test **circuit** is defined as the ... Phonetic Balance (PB), word length, **stress** position, word ...  
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S Au, BH Leung - Solid-State Circuits, IEEE Journal of, 1997 - ieeexplore.ieee.org  
 ... means higher **stress** for the thin oxide in fine ... The scaled-down clockbooster **circuit** is also used to ... based, does not show significant SNR **degradation** until the op ...

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JJ Sun, CM Osburn - Electron Devices, IEEE Transactions on, 1998 - ieeexplore.ieee.org  
... the effect of Miller capacitance on circuit speed ... A slight degradation of drain-induced-barrier-lowering ... Channel MOS Transistors During Channel-Hot-Hole Stress ...

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**Digital and Analog Communication Systems K. Sam Shanmugam**

RE Ziemer - ieeexplore.ieee.org  
... some knowledge of **circuit analysis** and linear system ... Silver- man (motion and noise degradation), Nahi, Woods ... Several authors **stress** line- / by-line techniques ...  
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**AN OVERVIEW OF VARIABLE RATE SPEECH CODING FOR CELLULAR NETWORKS**

A Gersho, E Paksoy - ieeexplore.ieee.org  
... was studied by Chou and Lookabaugh [7] where joint optimization of vector **quantization** and entropy coding ... Often, the **degradation** in reproduced speech is caused  
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